



DOCUMENT CHANGE REQUEST

DCR number 268 Changes required for: General

Date: 2006/07/24

Date sent: 2006/07/24

Originator: Ron Fidler

Organisation: ESA/ESTEC

Status: IMPLEMENTED

Title: Diodes, Silicon, Power Rectifier, High Efficiency, Fast Recovery, based on type BYV 52-200

Number: 5103/030

Issue: 1

Other documents affected:

Page:

Total re-write - see below

Paragraph:

Total re-write - see below

Original wording:

Proposed wording:

Total reformat of this Detail Specification as part of the ongoing conversion to the ESCC format.
See below for summary of changes and attached Issue 2 Draft A of the specification.

Note:

Known support for active procurement against this specification includes the following Manufacturer:
STM (ESCC QPL listed for Variant 01).

Summary of changes to the current format, layout and content is as follows:

1. Rewording and restructure of various sections and paragraphs of the specification plus other editorial changes based on the layout and editorial content of other Detail Specifications already converted to ESCC format.
2. Deletion of any redundant paragraphs and information, e.g. the mechanical paragraph.
3. Figure 1 Parameter Derating Requirements - moved to be a note to the Maximum Ratings table.
4. New paragraph for Beryllium Oxide handling precautions added for type variants with the TO-245 package.
5. Figure 2(a) - Dimensions .H., .J. and .K. corrected from "Typical" to "BSC". Dimension .I. corrected to .fl. and .M. to .fM..
6. Para 4.3.2 - Weight requirements moved to Component Type Variants table.
7. Requirement for marking of the testing level letter from the ESCC Component Number deleted as per latest ESCC



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No. 21700.

8. Table 2 . The test condition for .trr. corrected to .Test Condition A..

9. Table 3 (High & Low Temp Electricals) - 100% inspection changed to a sample of 5 components with 0 failures (or 100%) (In line with new generic 5000 Issue 2). New Note added to cover this. Test temperatures with tolerances added.

10. Table 4 - Absolute limits from Table 2 have been added for information.

Justification:

Justification (see also change details for each item above):

1. Part of the ongoing activity of conversion of cover-sheeted ESA/SCC specifications to the ESCC format.
2. To make the format and presentation consistent with the various other ESCC Detail Specifications already converted to ESCC format (e.g. 54HCMOS and CMOS 4000B series of ESCC IC specifications).
3. To make the content consistent with the ESCC format Generic Specification No.5000 issue 2.
4. To make corrections to several technical errors in the previous issue.

Attachments:

N/A

Modifications:

N/A

Approval signature:

Date signed:

2006-07-24